Se	arch	Notes	

es	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/614,875 Examiner	SATOH ET AL.	
	John Q. Nguyen	3654	

<u> </u>			•
SEARCHED			
Class	Subclass	Date	Examiner
242	338.1 338.3 343 348	10/5/2005	JN
360	132	10/5/2005	JN
			*

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
interferen	search, see ce search tout	10/5/2005	JN

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
· · · · · · · · · · · · · · · · · · ·		